

N-Channel 30-V(D-S) MOSFET

GENERAL DESCRIPTION

The ME4856 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density , DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching , and low in-line power loss are needed in a very small outline surface mount package.

FEATURES

- $R_{DS(ON)} \leq 6m\Omega @ V_{GS}=10V$
- $R_{DS(ON)} \leq 8.5m\Omega @ V_{GS}=4.5V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

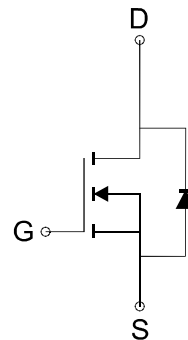
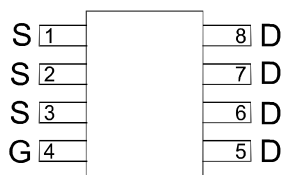
APPLICATIONS

- Power Management in Note book
- Battery Powered System
- DC/DC Converter
- Load Switch

PIN CONFIGURATION

(SOP-8)

Top View



N-Channel MOSFET

Absolute Maximum Ratings (TA=25°C Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DSS}	30	V
Gate-Source Voltage	V_{GSS}	± 20	V
Continuous Drain Current (T _J =150°C)	I_D	T _A =25°C	17
		T _A =70°C	14
Pulsed Drain Current	I_{DM}	50	A
Continuous Source Current (Diode Conduction)	I_S	2.7	A
Pulse Source-Drain Diode Current	I_{SM}	50	A
Maximum Power Dissipation	P_D	T _A =25°C	3.0
		T _A =70°C	2.0
Operating Junction Temperature	T _J	-55 to 150	°C
Thermal Resistance-Junction to Ambient*	$R_{\theta JA}$	T ≤ 10 sec	30
		Steady State	60
thermal Resistance-Junction to Case	$R_{\theta JC}$	34	°C/W

* The device mounted on 1in² FR4 board with 2 oz copper

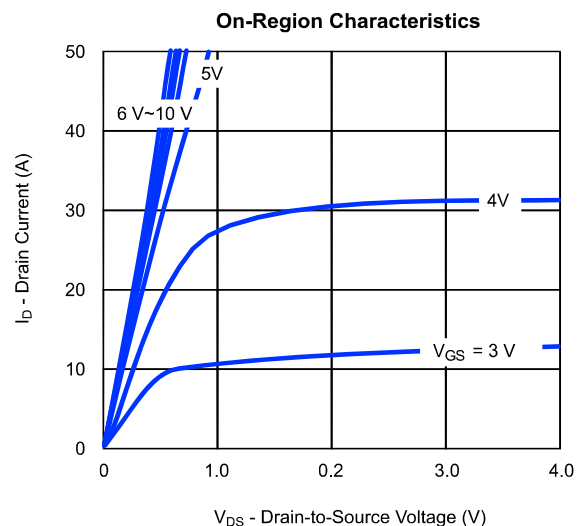
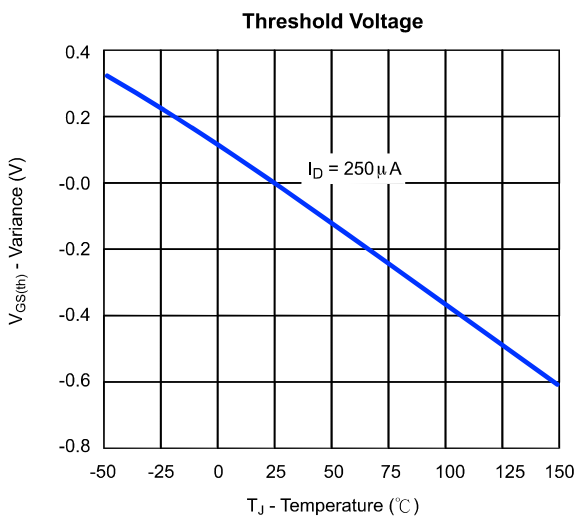
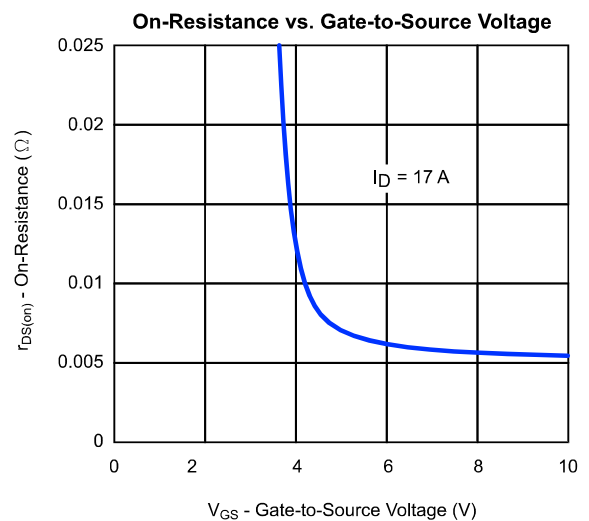
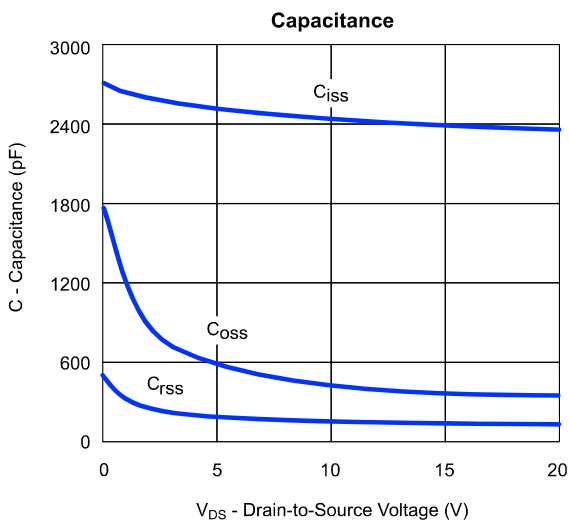
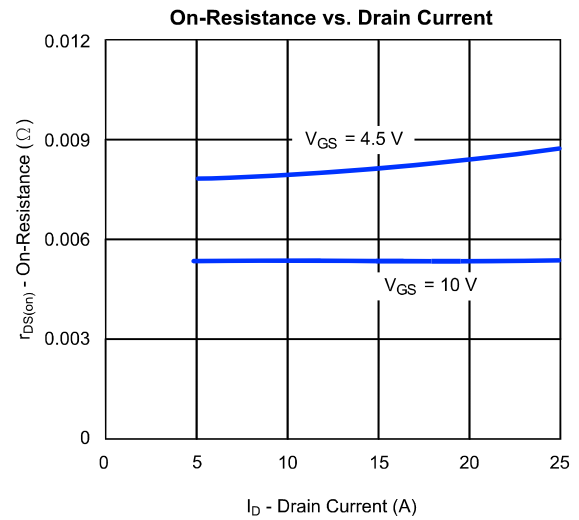
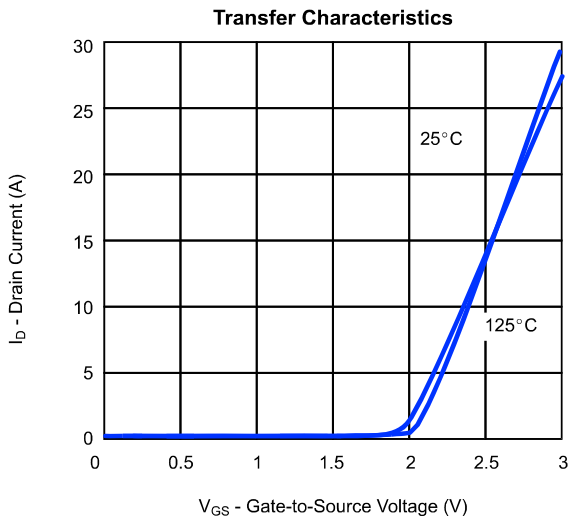
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Electrical Characteristics (T_A=25°C Unless Otherwise Specified)

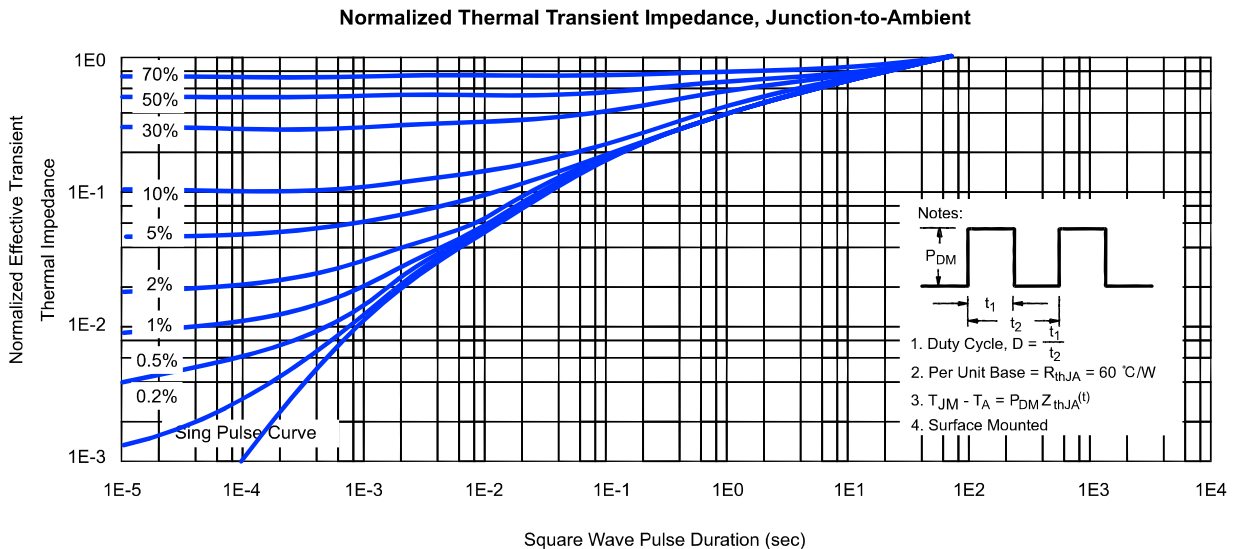
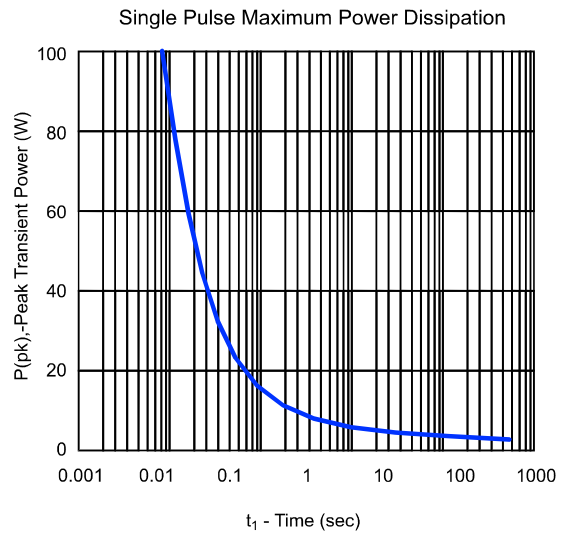
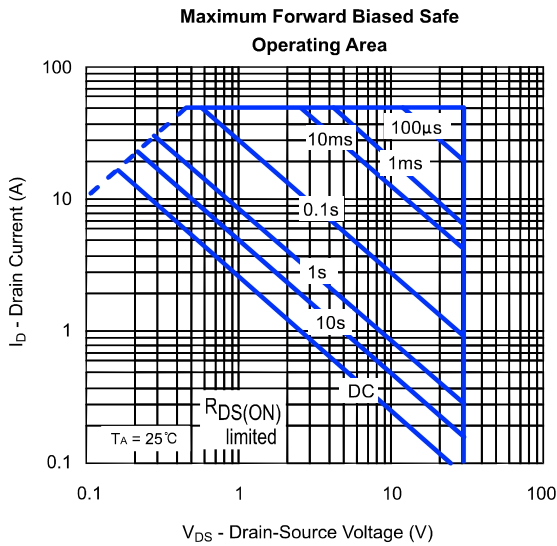
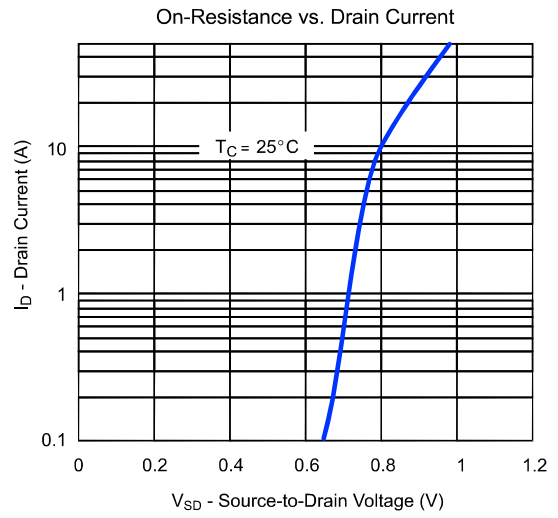
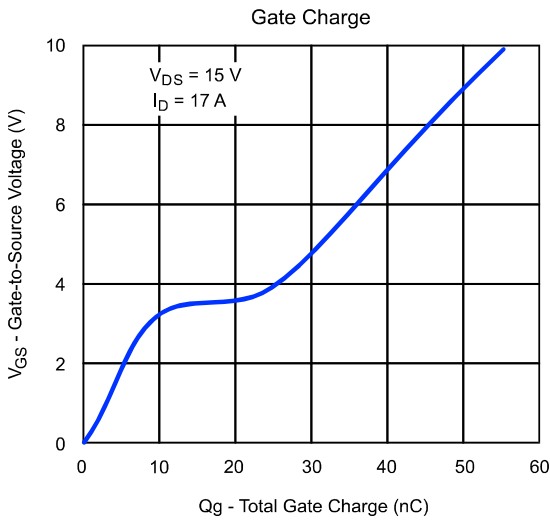
Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250 μA	30			V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250 μA	1.3	1.8	3	V
I _{GSS}	Gate Leakage Current	V _{DS} =0V, V _{GS} =±20V			±100	nA
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V			1	μA
		V _{DS} =30V, V _{GS} =0V T _J =70°C			5	
I _{D(ON)}	On-State Drain Current ^a	V _{DS} ≥5V, V _{GS} =10V	40			A
R _{DS(ON)}	Drain-Source On-State Resistance ^a	V _{GS} =10V, I _D =10A		4.5	6	mΩ
		V _{GS} =4.5V, I _D =7.5A		6.5	8.5	
G _{FS}	Forward Transconductance ^a	V _{DS} =15V, I _D =17A		14		S
V _{SD}	Diode Forward Voltage	I _S =2.7A, V _{GS} =0V		0.72	1.1	V
DYNAMIC						
Q _g	Total Gate Charge(4.5V)	V _{DS} =15V, V _{GS} =4.5V, I _D =17A		55	60	nC
Q _g	Total Gate Charge(10V)	V _{DS} =15V, V _{GS} =10V, I _D =17A		29		
Q _{gs}	Gate-Source Charge			10		
Q _{gd}	Gate-Drain Charge			15		
C _{iss}	Input capacitance	V _{DS} =15V, V _{GS} =0V, f=1.0MHz		2400	2700	pF
C _{oss}	Output Capacitance			350		
C _{rss}	Reverse Transfer Capacitance			110		
R _g	Gate-Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	0.7	1.2	2.0	Ω
t _{d(on)}	Turn-On Delay Time	V _{DD} =15V, R _L =15Ω I _D =1A, V _{GEN} =10V R _G =6Ω		23	30	ns
t _r	Turn-On Rise Time			12	16	
t _{d(off)}	Turn-Off Delay Time			86	111	
t _f	Turn-Off Fall Time			12	16	
t _{rr}	Source-Drain Reverse Recovery Time	I _F =2.7A, di/dt=100A/μs		40	60	
Q _{rr}	Body diode Reverse Recovery charge	I _F =2.9A, di/dt=100A/μs		36	60	nC

Note: a: Pulse test: pulse width≤300us, duty cycle≤2%

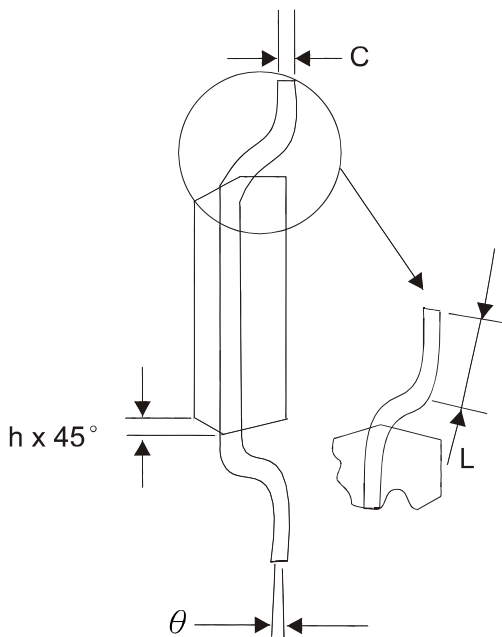
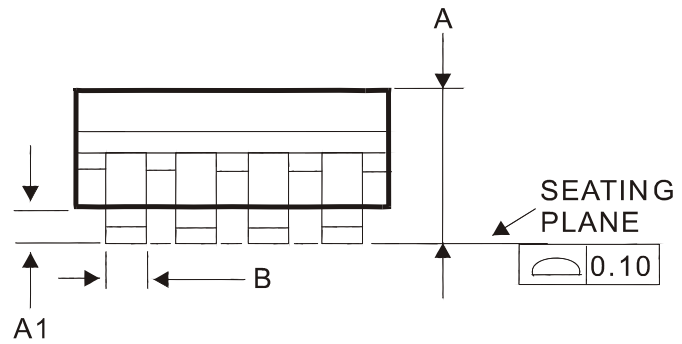
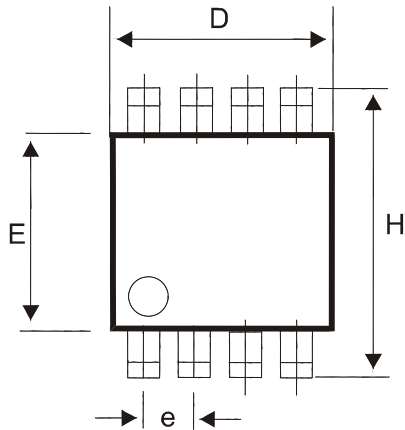
Typical Characteristics (T_J = 25°C Noted)



Typical Characteristics (T_J = 25°C Noted)



SOP-8 Package Outline



DIM	MILLIMETERS	
	MIN	MAX
A	1.35	1.75
A1	0.10	0.25
B	0.35	0.49
C	0.18	0.25
D	4.80	5.00
E	3.80	4.00
e	1.27 BSC	
H	5.80	6.20
h	0.25	0.50
L	0.40	1.25
θ	0°	7°

Note: 1. Refer to JEDEC MS-012AA.

2. Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusions or gate burrs shall not exceed 0.15 mm per side.